

Midterm Exam (20%)

ENEE 359a: Digital VLSI Design, Spring 2007 The Ides of March, Opening Round of the NCAA Tournament

This exam should take you less than an hour: 5 questions, 10 minutes apiece. The exam is closed book, closed notes.

Note that each question is worth the same number of points; this means you should do those questions you find easy first.

Solutions

Score:

Name:_____

Total:		
Problem 5:	out of 4	
Problem 4:	out of 4	
Problem 3:	out of 4	
Problem 2:	out of 4	
Problem 1:	out of 4	

Grade Distribution: 20 - X X 19 - X X X X 18 - X X X 17 -16 - X 15 - X X X 14 -13 - X 12 -11 -10 -9 - X

1. Consider the following stick diagram. Draw the electrically equivalent transistor-level schematic. What logic equation does the circuit implement?



solution:



2. Consider the logical expression out = (ab + cd). Convert this to a schematic diagram for static CMOS logic, then convert it to a stick-diagram layout (as in question 1).

some equivalent solutions (there is more than one correct answer):





3. Provide a side-view diagram for each of the cuts X and Y through the layout below. Be sure to label each of the strata. Label your endpoints for the X cut, so it is clear which end is which.



solution:





4. Consider the function $out = -((a + bc) \cdot d)$. Draw the circuit and size the transistors: size all NMOS and PMOS transistors so that the PUN and PDN each has equivalent resistance to a minimum-sized MOSFET, and then take into account the fact that $\mu_n = r \cdot \mu_p$ where r = 2.5 (i.e. the resistance of a unit PMOS device is 2.5 times that of a unit NMOS device).

Important: Assume the circuit is implemented in a 60nm technology and that the dimensions of a **minimum-sized MOSFET** in this technology are **90nm width x 60nm length**. Express the dimensions of each MOSFET in the optimized circuit in <u>nanometers</u> (W nm x L nm). I.e., what is it that you are scaling?

some equivalent solutions (there is more than one correct answer):

min. device: $WxL = 90nm \times 60nm$



5. You have identified a critical path through a circuit, as shown below. Consider the path up to the jagged line; the 2-input NAND beyond simply represents the load being driven (it can be thought of as the input to a D-latch, for example). That NAND has been scaled by a factor of $7^3 \div 5^3$ which can be approximated by the value 2.8. Thus, the load NAND has C_{nand} approximately equal to 3.5 C_{in} . Find the scaling terms s_i for each gate and the optimized path delay. Assume that gamma=1, that r=3, and that the p_i terms are all equal (leave as "p").



Equations you might find useful:

Optimal gate effort
$$h = \sqrt[N]{GFB} = \sqrt[N]{H}$$

 $g_{nand} = \frac{n+r}{1+r}$ $g_{nor} = \frac{1+nr}{1+r}$ $f_{i,opt} = \frac{h}{g_i}$ Optimal delay $= t_{p0} \left(\sum p_i + \frac{N^N \sqrt{H}}{\gamma} \right)$
Sizing for gate $i = \left(\frac{g_1 s_1}{g_i}\right) \prod_{j=1}^{i-1} \left(\frac{f_j}{b_j}\right)$ $F = \frac{C_{load}}{C_{in}}$ $G = \prod_i g_i$

solution:
r=3
#1 #2 #3 #4 #5
n=2 n=2 g_L=5/4

$$g_1=1$$
 $g_2=5/4$ $g_3=7/4$ $g_4=7/4$ $g_5=5/4$ $C_L=7^3/5^3 \cdot 5/4$
 $h = \sqrt[N]{GFB} = \sqrt[n]{\left(1 \cdot \frac{5}{4} \cdot \frac{7}{4} \cdot \frac{7}{4} \cdot \frac{5}{4}\right) \cdot \left(\frac{7^3 \cdot 5}{5^3 \cdot 4}\right)} = \sqrt[n]{\left(\frac{7^5 \cdot 5^3}{5^3 \cdot 4^5}\right)} = \frac{7}{4}$
 $f_1 = \frac{7/4}{1}$ $f_2 = \frac{7/4}{5/4}$ $f_3 = \frac{7/4}{7/4}$ $f_4 = \frac{7/4}{7/4}$ $f_5 = \frac{7/4}{5/4}$ $\left(f_i = \frac{h}{g_i}\right)$
 $=7/4$ $=7/5$ $=1$ $=1$ $=7/5$
 $s_1 = 1$ $s_2 = \frac{1}{5/4} \cdot \frac{7}{4}$ $s_3 = \frac{1}{7/4} \cdot \frac{7}{4} \cdot \frac{7}{5}$ $s_4 = \frac{1}{7/4} \cdot \frac{7}{4} \cdot \frac{7}{5} \cdot 1$ $s_5 = \frac{1}{5/4} \cdot \frac{7}{4} \cdot \frac{7}{5} \cdot 1 \cdot 1$
 $= 7/5$ $= 7/5$ $= 7/5$ $= 49/25 \approx 2$
Delay $= t_{p0} \left(\sum p_i + \frac{N^N \sqrt{H}}{\gamma}\right) = t_{p0} \left(5p + \frac{35}{4}\right)$